

<b>Notice of References Cited</b>	Application/Control No. 10/822,023	Applicant(s)/Patent Under Reexamination CHURT ET AL.	
	Examiner David Q. Nguyen	Art Unit 2681	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2002/0198028 A1	12-2002	Tsumura, Toshihiro	455/564
*	B	US-2004/0137845 A1	07-2004	Vonheim et al.	455/041.2
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

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	X	

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